

TITLE: INSPECTING APPARATUS FOR SEMICONDUCTOR DEVICE
INVENTORS: Je-Hyoung RYU, et al.
SERIAL NO.:
DOCKET NO.: 1572.1243

FIG. 1

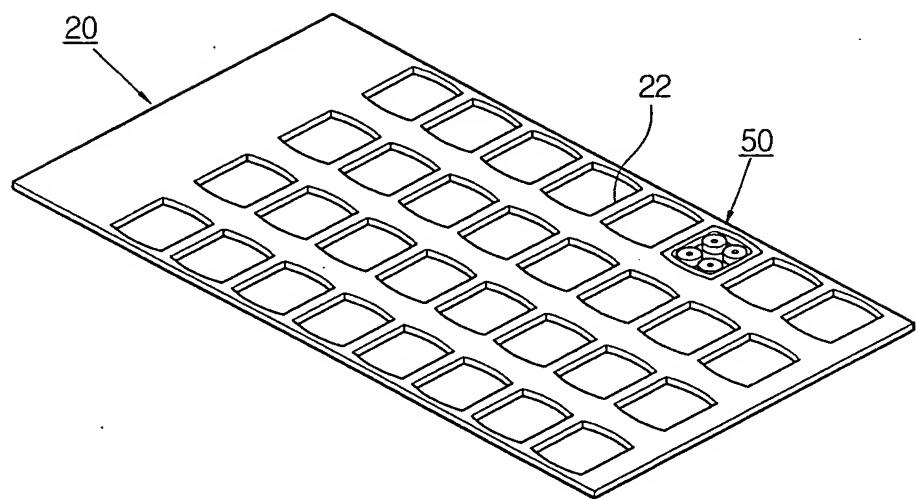


FIG. 2

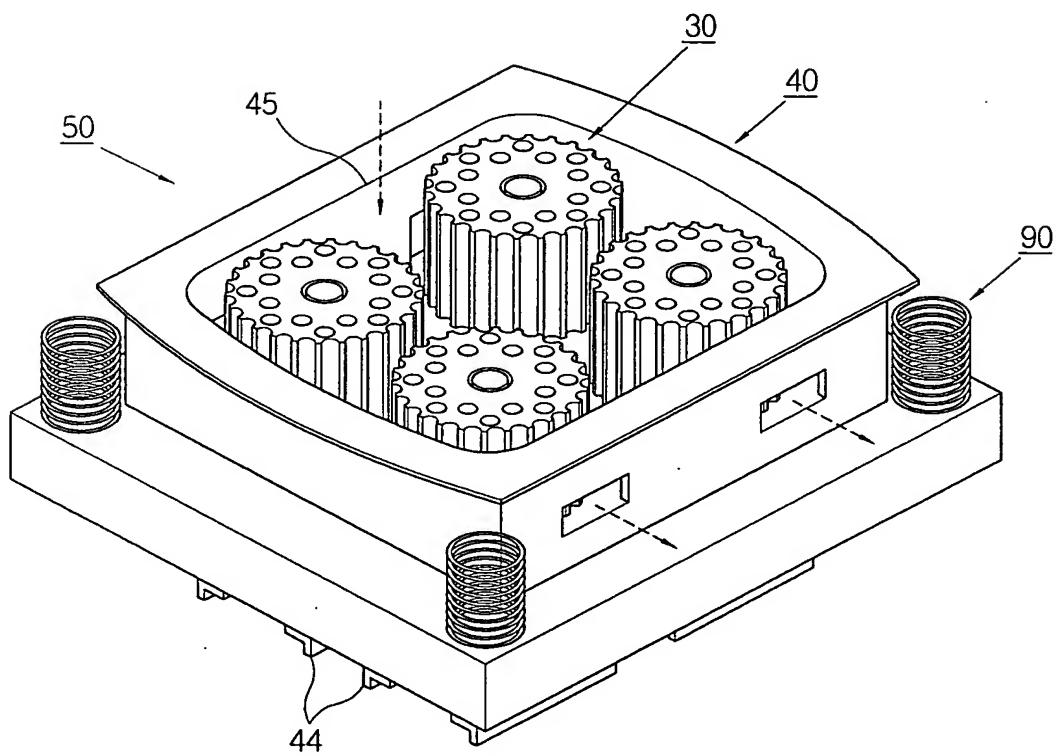
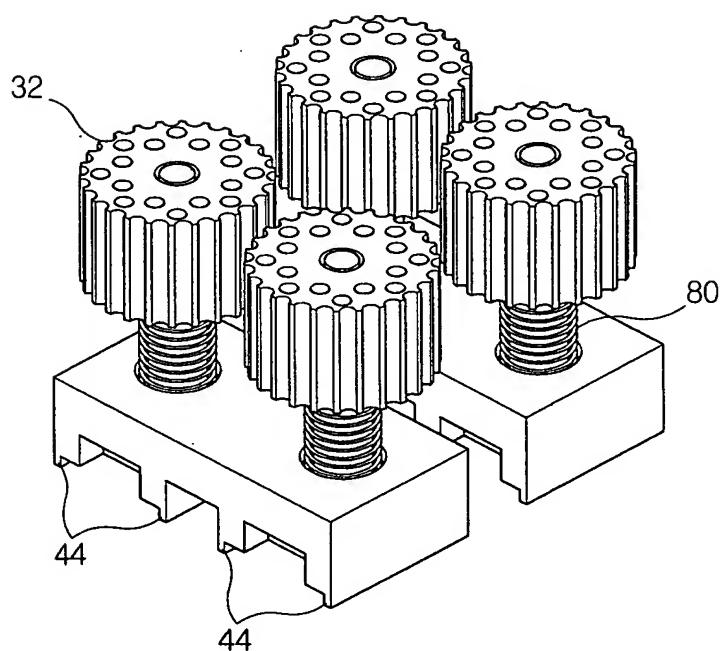


FIG. 3



TITLE: INSPECTING APPARATUS FOR SEMICONDUCTOR DEVICE
INVENTORS: Je-Hyoung RYU, et al.
SERIAL NO.:
DOCKET NO.: 1572.1243

FIG. 4

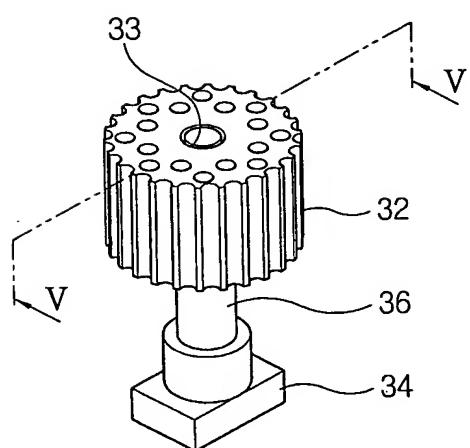


FIG. 5

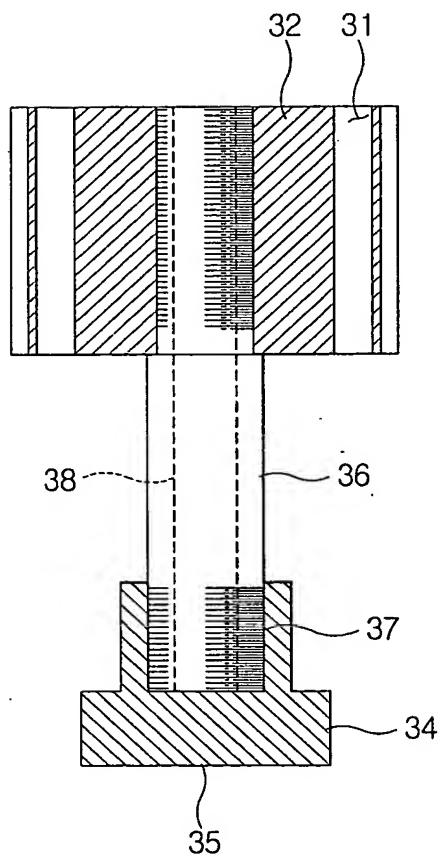


FIG. 6

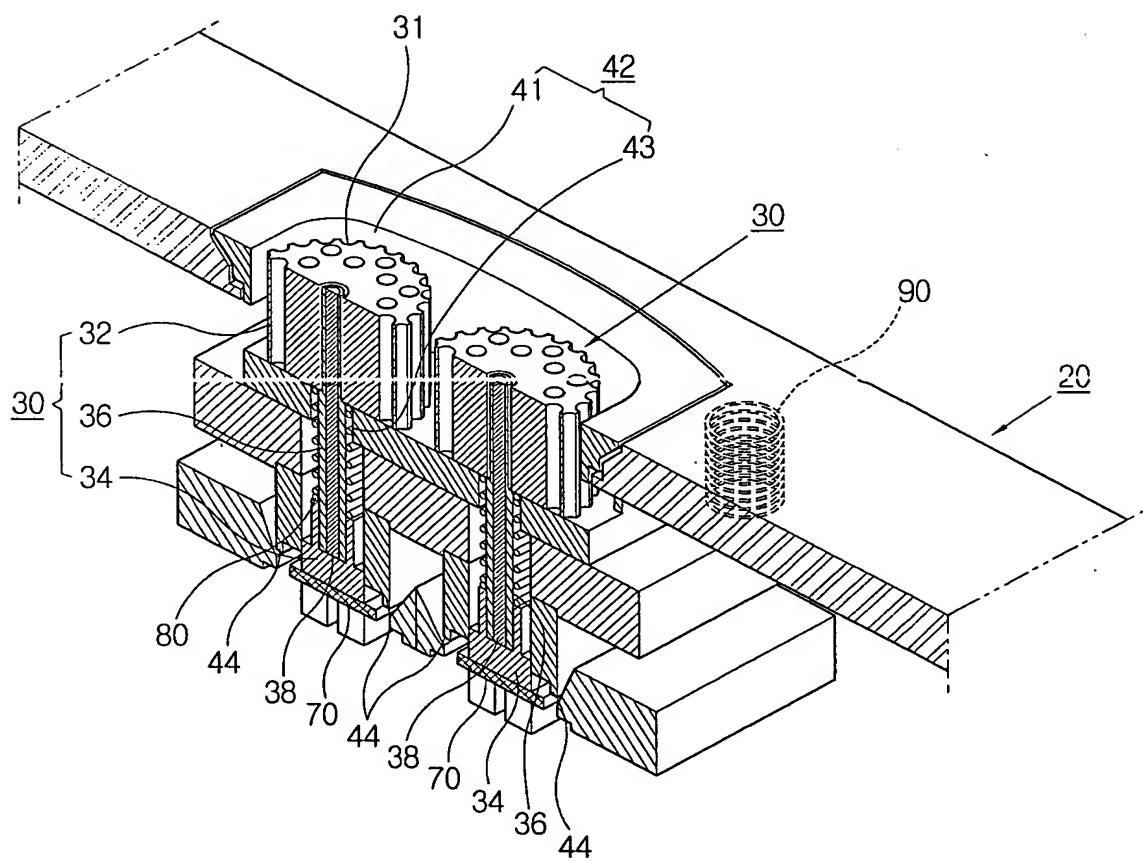


FIG. 7A

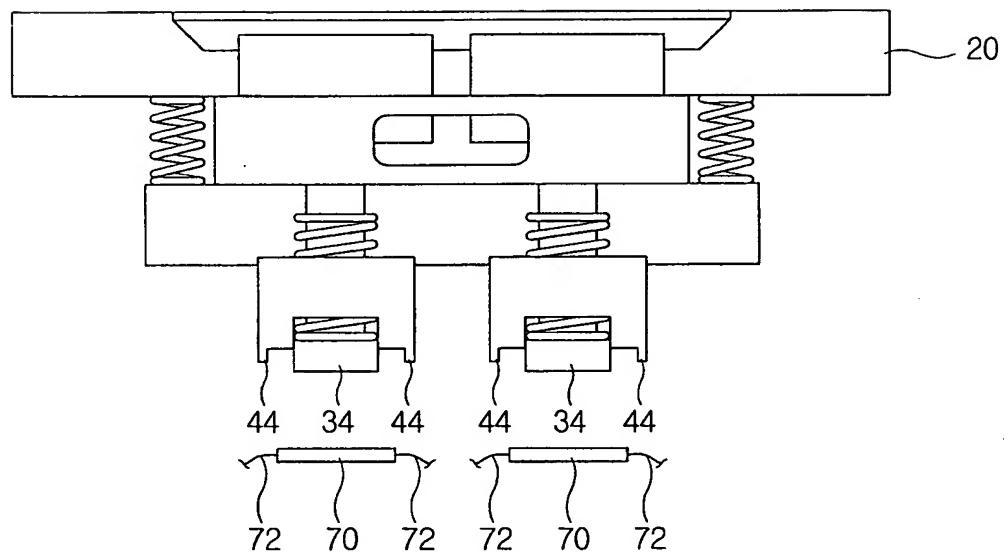


FIG. 7B

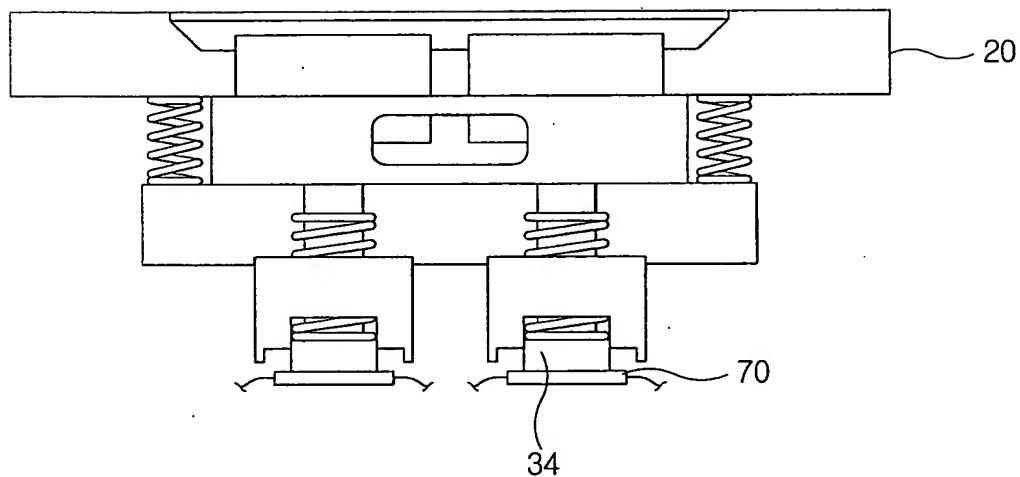


FIG. 7C

